

Sheet 1 of 1

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		ATTY. DOCKET NO. 46248		SERIAL NO. 10/765,085				
		APPLICANT Chae-Whan Lim et al.						
		FILING DATE January 28, 2004		GROUP Not Assigned				
<b>U.S. Patent Documents</b>								
		Patent No.	Date	Patentee	Class	Sub-class	Filing Date	
J.F.C.		5,101,438	3/31/1992	Kanda et al.	382	176	1/24/1991	
		5,995,657	11/30/1999	Sunakawa et al.	382	170	12/16/1997	
J.F.C.		4,876,732	10/24/1989	Miyagawa et al.	382	288	5/18/1987	
<b>Published U.S. Patent Application</b>								
		Patent No.	Pub. Date	Patentee	Class	Sub-class	Filing Date	
<b>Foreign Patent Documents or Foreign Patent Applications</b>								
		Document No.	Pub. Date	Country or Patent Office	Class	Sub-class	English Abstract	
							Yes	No
J.F.C.		0 431 960 A2	6/12/1991	EUROPE			X	
<b>OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)</b>								
J.F.C.		G. Kapogiannopoulos et al.: "A fast high precision algorithm for the estimation of skew angle using moments"; Proc. International Conference Signal Processing, Pattern Recognition, And Applications (SPPRA 2002), IASTED; 6/25/2002; Pages 275-279.						
		Su Chen et al.: "Automatic text skew estimation in document images"; Document Analysis And Recognition, 1995.; Proceedings Of The Third International Conference On Montreal, Que., Canada; 14-16; August 1995; Los Alamitos, CA, USA, IEEE Comput. Soc, US; vol. 2; August 14, 1995; Pages 1153-1156.						
		Osamu Nakamura et al.: "Extraction Of Photographic Area From Document Images" Electronics & Communications In Japan, Part I - Communications, Wiley, Hoboken, NJ, US; vol. 71, no. 6; June 1, 1988; Pages 76-85.						
J.F.C.		J.H. Park et al.: "Skew correction of business card images in PDA"; IEEE Conf. On Communications, Computers And Signal Processing (PACRIM 2003); August 28, 2003.						
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw Line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

J.F. Cunningham, 7/30/07  
Examiner